

# Normally – OFF Silicon Carbide Junction Transistor

 $V_{DS}$  = 1200 V  $V_{DS(ON)}$  = 1.4 V  $I_{D}$  = 20 A  $R_{DS(ON)}$  = 70 m $\Omega$ 

#### **Features**

- 175 °C maximum operating temperature
- Temperature independent switching performance
- Gate oxide free SiC switch
- Suitable for connecting an anti-parallel diode
- · Positive temperature coefficient for easy paralleling
- · Low gate charge
- · Low intrinsic capacitance

#### **Package**

• RoHS Compliant





**TO-263** 

## **Advantages**

- · Low switching losses
- Higher efficiency
- High temperature operation
- · High short circuit withstand capability

## **Applications**

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- · Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

#### Maximum Ratings unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit
Drain – Source Voltage	$V_{DS}$	V <sub>GS</sub> = 0 V	1200	V
Continuous Drain Current	I <sub>D</sub>	T <sub>C,MAX</sub> = 95 °C	20	Α
Gate Peak Current	$I_{GM}$		10	Α
Turn-Off Safe Operating Area	RBSOA	$T_{VJ}$ = 175 °C, $I_{G}$ = 1 A, Clamped Inductive Load	$I_{D,max} = 20$ $\emptyset V_{DS} \le V_{DSmax}$	Α
Short Circuit Safe Operating Area	SCSOA	$T_{VJ}$ = 175 °C, $I_G$ = 1 A, $V_{DS}$ = 800 V, Non Repetitive	20	μs
Reverse Gate – Source Voltage	$V_{SG}$		30	V
Reverse Drain – Source Voltage	$V_{SD}$		25	V
Power Dissipation	P <sub>tot</sub>	T <sub>C</sub> = 95 °C	157	W
Storage Temperature	T <sub>stg</sub>		-55 to 175	°C

# Electrical Characteristics at $T_j$ = 175 °C, unless otherwise specified

Downwood on	Comple at	Combal Conditions		Values		1114
Parameter	Symbol	Conditions -	min.	typ.	max.	Unit
On Characteristics						
		I <sub>D</sub> = 20 A, I <sub>G</sub> = 400 mA, T <sub>j</sub> = 25 °C		1.4		
Drain – Source On Voltage	$V_{DS(ON)}$	$I_D = 20 \text{ A}, I_G = 800 \text{ mA}, T_j = 125 ^{\circ}\text{C}$		1.6		V
		$I_D = 20 \text{ A}, I_G = 1600 \text{ mA}, T_j = 175 °C$		2.2		
		$I_D = 20 \text{ A}, I_G = 400 \text{ mA}, T_j = 25 ^{\circ}\text{C}$		70		
Drain – Source On Resistance	$R_{DS(ON)}$	$I_D = 20 \text{ A}, I_G = 800 \text{ mA}, T_j = 125 ^{\circ}\text{C}$		80		mΩ
	, ,	$I_D = 20 \text{ A}, I_G = 1600 \text{ mA}, T_j = 175 ^{\circ}\text{C}$		110		
Cata Famuurd Valtaga	$V_{GS(FWD)}$	I <sub>G</sub> = 500 mA, T <sub>j</sub> = 25 °C		3.3		V
Gate Forward Voltage		$I_G = 500 \text{ mA}, T_j = 175 ^{\circ}\text{C}$		3.1		v
DC Current Gain	β	$V_{DS} = 5 \text{ V}, I_{D} = 20 \text{ A}, T_{i} = 25 ^{\circ}\text{C}$		TBD		
	р	$V_{DS} = 5 \text{ V}, I_D = 20 \text{ A}, T_j = 175 °C$		TBD		
Off Characteristics						
		V <sub>R</sub> = 1200 V, V <sub>GS</sub> = 0 V, T <sub>j</sub> = 25 °C		1.1		
Drain Leakage Current	I <sub>DSS</sub>	$V_R = 1200 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 125 \text{ °C}$		1.6		μΑ
-		$V_R = 1200 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 175 ^{\circ}\text{C}$		2.1		•
Gate Leakage Current	I <sub>sg</sub>	$V_{SG} = 20 \text{ V}, T_i = 25 ^{\circ}\text{C}$	•	20		nA



Electrical Characteristics at  $T_j$  = 175 °C, unless otherwise specified

Parameter	Symbol	Symbol Conditions	Values		Unit		
Parameter	Symbol Conditions —		min.	typ.	max.	Unit	
Capacitance Characteristics							
Gate-Source Capacitance	C <sub>qs</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz		tbd		pF	
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V}, V_{D} = 1 \text{ V}, f = 1 \text{ MHz}$		tbd		pF	
Reverse Transfer/Output Capacitance	$C_{rss}/C_{oss}$	$V_D = 1 V, f = 1 MHz$		tbd		pF	
Switching Characteristics							
Turn On Delay Time	t <sub>d(on)</sub>			tbd		ns	
Rise Time	$V_{DD} = 800 \text{ V}, I_D = 20 \text{ A},$			tbd		ns	
Turn Off Delay Time	$t_{d(off)}$	$R_{G(on)} = R_{G(off)} = 44 \Omega,$ $V_{GS} = -8/15 \text{ V, L} = 1.1 \text{ mH,}$		tbd		ns	
Fall Time	t <sub>f</sub>	FWD = GB40SLT12,		tbd		ns	
Turn-On Energy Per Pulse	E <sub>on</sub>	T <sub>j</sub> = 25 °C		tbd		μJ	
Turn-Off Energy Per Pulse	$E_{off}$	Refer to Figure 15 for gate current		tbd		μJ	
Total Switching Energy	$E_ts$	waveform		tbd		μJ	
Turn On Delay Time	t <sub>d(on)</sub>			tbd			
Rise Time	t <sub>r</sub>	$V_{DD} = 800 \text{ V, } I_D = 20 \text{ A,}$ $R_{G(on)} = R_{G(off)} = 44 \Omega,$ $V_{GS} = -8/15 \text{ V, } L = 1.1 \text{ mH,}$		tbd		ns	
Turn Off Delay Time	$t_{d(off)}$			tbd		ns	
Fall Time	t <sub>f</sub>	FWD = GB40SLT12.		tbd		ns	
Turn-On Energy Per Pulse	E <sub>on</sub>	T <sub>j</sub> = 175 °C Refer to Figure 15 for gate current		tbd		μJ	
Turn-Off Energy Per Pulse	E <sub>off</sub>			tbd		μJ	
Total Switching Energy	$E_ts$	waveform		tbd		μJ	
Thermal Characteristics							
Thermal resistance, junction - case	$R_{thJC}$			0.51		°C/W	

	re	

TBD

TBD

Figure 1: Typical Output Characteristics at 25 °C

Figure 2: Typical Output Characteristics at 125 °C



TBD

**TBD** 

Figure 3: Typical Output Characteristics at 175 °C

Figure 4: Typical Gate Source I-V Characteristics vs. Temperature

**TBD** 

TBD

Figure 5: Normalized On-Resistance and Current Gain vs. Temperature

Figure 6: Typical Blocking Characteristics

**TBD** 

TBD

Figure 7: Capacitance Characteristics

Figure 8: Capacitance Characteristics



TBD

**TBD** 

Figure 9: Typical Hard-switched Turn On Waveforms

Figure 10: Typical Hard-switched Turn Off Waveforms

TBD

Figure 11: Typical Turn On Energy Losses and Switching Times vs. Temperature

Figure 12: Typical Turn Off Energy Losses and Switching Times vs. Temperature

TBD

TBD

Figure 13: Typical Turn On Energy Losses vs. Drain Current

Figure 14: Typical Turn Off Energy Losses vs. Drain Current



**TBD** 

TBD

Figure 15: Typical Gate Current Waveform

Figure 16: Typical Hard Switched Device Power Loss vs. Switching Frequency <sup>1</sup>

**TBD** 

TBD

Figure 17: Power Derating Curve

Figure 18: Forward Bias Safe Operating Area

TBD

TBD

Figure 19: Turn-Off Safe Operating Area

Figure 20: Transient Thermal Impedance

<sup>&</sup>lt;sup>1</sup> – Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.



#### **Gate Drive Technique (Option #1)**

To drive the GA20JT12-263 with the lowest gate drive losses, please refer to the dual voltage source gate drive configuration described in Application Note AN-10B (http://www.genesicsemi.com/index.php/references/notes).

## **Gate Drive Technique (Option #2)**

The GA20JT12-263 can be effectively driven using the IXYS IXDN614 / IXDD614 non-inverting gate driver IC or a comparable product. A typical gate driver configuration along with component values using this driver is offered below. Additional information is available in GeneSiC Application Note AN-10A and from the manufacturer at www.ixys.com.

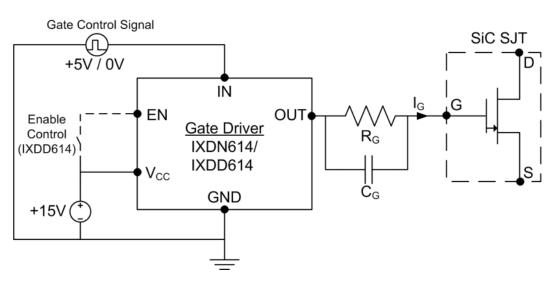


Figure 21: Recommended Gate Diver Configuration (Option #2)

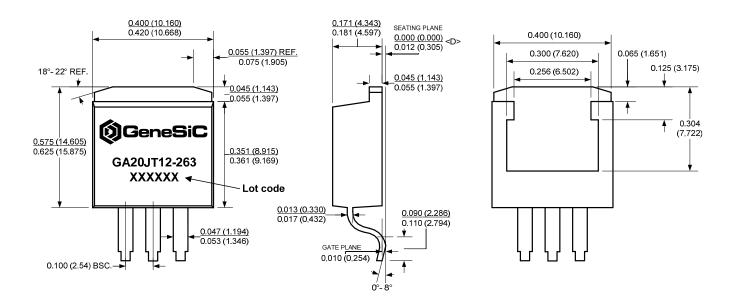
Parameter	Symbol	Canditions	Values			I I m ! 4	
Parameter	Зупівої	Symbol Conditions		typ.	max.	Unit	
Option #2 Gate Drive Conditions (IX	DD614/IXDN614)						
Supply Voltage	V <sub>CC</sub>		-0.3	15	40	V	
Gate Control Input Signal, Low	IN		-5.0	0	0.8	V	
Gate Control Input Signal, High	IN		3.0	5.0	V <sub>CC</sub> +0.3	V	
Enable, Low	EN	IXDD614 Only			1/3*V <sub>cc</sub>	V	
Enable, High	EN	IXDD614 Only	2/3*V <sub>cc</sub>			V	
Output Voltage, Low	$V_{OUT}$				0.025	V	
Output Voltage, High	$V_{OUT}$		V <sub>CC</sub> -0.025			V	
Output Current, Peak	I <sub>OUT</sub>	Package Limited		tbd	14	Α	
Output Current, Continuous	I <sub>OUT</sub>			tbd	4.0	Α	
Passive Gate Components							
Gate Resistance	$R_{G}$	I <sub>G</sub> ≈ 0.5 A	5	tbd		Ω	
Gate Capacitance	C <sub>G</sub>	I <sub>G</sub> ≈ 0.5 A		tbd		nF	



## **Package Dimensions:**

**TO-263** 

#### **PACKAGE OUTLINE**



#### NOTE

- 1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
- 2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History						
Date Revision Comments Supersedes						
2013/09/12	0	Initial release				

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# **SPICE Model Parameters**

Copy the following code into a SPICE software program for simulation of the GA20JT12 SJT device.

```
MODEL OF GeneSiC Semiconductor Inc.
     $Revision: 1.0
     $Date: 26-AUG-2013
    GeneSiC Semiconductor Inc.
    43670 Trade Center Place Ste. 155
    Dulles, VA 20166
    http://www.genesicsemi.com/index.php/sic-products/sjt
    COPYRIGHT (C) 2013 GeneSiC Semiconductor Inc.
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* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
.model GA20JT12 NPN
+ IS
         5.00E-47
+ ISE
         1.26E-28
+ EG
          3.2
+ BF
         100
+ BR
         0.55
         700
+ IKF
+ NF
         1
+ NE
         0.26
+ RB
+ RC
         0.055
+ CJC
        6.98E-10
+ VJC
         3
         0.5
+ MJC
+ CJE
         2.22E-9
+ VJE
         3
+ MJE
         0.5
+ XTI
          -1.2
+ XTB
+ TRC1
         7.00E-3
+ VCEO
          1200
+ ICRATING 20
+ MFG
      GeneSiC_Semiconductor
```

\* End of GA20JT12 SPICE Model